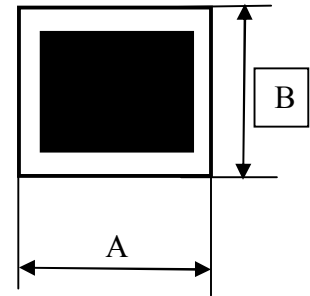


**Chip TVS diode.**
**Die size: 22,8\*14,6mil.**

Mechanical date: A= 580um; B=370um. Chip thickness –230+/-20um.  
 Scribe Line Width – 60um.  
 Top side – Anode. Al metallization for wire bond.

Back side- Cathode. Metallization Ti- Ni-Ag for soldering.


**Limiting values**

Parameter	Symbol	Conditions	Value	Unit
Working Peak Reverse Voltage	$V_{RWM}$		12,0.	V
Peak Pulse Power	$P_{pp}$	$t_p = 8/20\mu S$	400*	W
Max. Peak Pulse Current	$I_{pp}$	$t_p = 8/20\mu S$	17,0*	A
Electrostatic discharge	$V_{ESD}$	IEC 61000-4-2. Level-4.	+/-8,0 –Contact. +/-15,0 – Air.	kV
Max.Junction Temperature	$T_j$		+150	°C

**Characteristics .T<sub>j</sub>=25°C.**

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$I_R$	Diode reverse leakage current.	$V_R = 12,0V$	-	-	0,9	uA
$V_{BR}$	Breakdown voltage.	$I_R = 1mA$	12,7	-	16,7	V
$C_j$	Diode capacitance .	$F = 1MHz, V_R = 0 V.$	-	110	130	pF
$V_{CL}$	Clamping voltage	$I_R = 5A, t_p = 8/20\mu S$ $I_R = 17A, t_p = 8/20\mu S$	-	-	18,2* 24,2*	V

\*- For Device testing.